# **Switching Transistor PNP Silicon**





MMBT4403LT1

### MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	VCEO	-40	Vdc
Collector-Base Voltage	VCBO	-40	Vdc
Emitter-Base Voltage	VEBO	-5.0	Vdc
Collector Current — Continuous	lc	-600	mAdc



#### THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Total Device Dissipation FR-5 Board <sup>(1)</sup> TA = $25^{\circ}$ C	PD	225	mW
Derate above 25°C		1.8	mW/°C
Thermal Resistance, Junction to Ambient	R <sub>θJA</sub>	556	°C/W
Total Device Dissipation Alumina Substrate. <sup>(2)</sup> $T_{\Delta} = 25^{\circ}C$	PD	300	mW
Derate above 25°C		2.4	mW/°C
Thermal Resistance, Junction to Ambient	R <sub>0JA</sub>	417	°C/W
Junction and Storage Temperature	Tj, T <sub>stg</sub>	-55 to +150	0°C

# 勝特力材料 886-3-5753170 胜特力电子(上海) 86-21-54151736 胜特力电子(深圳) 86-755-83298787 Http://www. 100y. com. tw

#### **DEVICE MARKING**

MMBT4403LT1 = 2T	N.COM.TW			
ELECTRICAL CHARACTERISTICS (T <sub>A</sub> = 25°C unless otherwise noted)				
Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS	TOO COMP.	M	VIII	W. Port
Collector-Emitter Breakdown Voltage(3) ( $I_C = -1.0$ mAdc, $I_B = 0$ )	V(BR)CEO	-40	-1	Vdc
Collector-Base Breakdown Voltage ( $I_C = -0.1 \text{ mAdc}, I_E = 0$ )	V(BR)CBO	-40	_ <	Vdc
Emitter-Base Breakdown Voltage ( $I_E = -0.1 \text{ mAdc}, I_C = 0$ )	V(BR)EBO	-5.0	× –	Vdc
Base Cutoff Current (V <sub>CE</sub> = -35 Vdc, V <sub>EB</sub> = -0.4 Vdc)	IBEV		-0.1	μAdc
Collector Cutoff Current ( $V_{CE} = -35 \text{ Vdc}, V_{EB} = -0.4 \text{ Vdc}$ )	ICEX	_	-0.1	μAdc

1. FR-5 =  $1.0 \times 0.75 \times 0.062$  in.

2. Alumina =  $0.4 \times 0.3 \times 0.024$  in. 99.5% alumina.

3. Pulse Test: Pulse Width  $\leq$  300 µs, Duty Cycle  $\leq$  2.0%.

Thermal Clad is a trademark of the Bergquist Company.

Preferred devices are Motorola recommended choices for future use and best overall value.



# MMBT4403LT1

	0,11001	Min	Max	Unit
SN CHARACTERISTICS	100Y.CO	WILL		
DC Current Gain (I <sub>C</sub> = -0.1 mAdc, V <sub>CE</sub> = -1.0 Vdc) (I <sub>C</sub> = -1.0 mAdc, V <sub>CE</sub> = -1.0 Vdc) (I <sub>C</sub> = -10 mAdc, V <sub>CE</sub> = -1.0 Vdc) (I <sub>C</sub> = -150 mAdc, V <sub>CE</sub> = -2.0 Vdc)(3) (I <sub>C</sub> = -500 mAdc, V <sub>CE</sub> = -2.0 Vdc)(3) (I <sub>C</sub> = -500 mAdc, V <sub>CE</sub> = -2.0 Vdc)(3)	hFE	30 60 100 100 20	 	_
Collector-Emitter Saturation Voltage <sup>(3)</sup> ( $I_C = -150 \text{ mAdc}, I_B = -15 \text{ mAdc}$ ) ( $I_C = -500 \text{ mAdc}, I_B = -50 \text{ mAdc}$ )	V <sub>CE(sat)</sub>	X. <u>C</u> OM	-0.4 -0.75	Vdc
Base-Emitter Saturation Voltage (3) $(I_C = -150 \text{ mAdc}, I_B = -15 \text{ mAdc})$ $(I_C = -500 \text{ mAdc}, I_B = -50 \text{ mAdc})$	V <sub>BE(sat)</sub>	-0.75 	-0.95 -1.3	Vdc
SMALL-SIGNAL CHARACTERISTICS	WW	100	CO <sub>M.,</sub>	N/
Current-Gain — Bandwidth Product ( $I_C = -20$ mAdc, $V_{CE} = -10$ Vdc, f = 100 MHz)	fT	200	.co <u>M</u> .	MHz
Collector–Base Capacitance ( $V_{CB} = -10$ Vdc, $I_E = 0$ , f = 1.0 MHz)	C <sub>cb</sub>	N N <del>1.</del> 100	8.5	pF
Emitter–Base Capacitance ( $V_{BE} = -0.5 \text{ Vdc}, I_{C} = 0, f = 1.0 \text{ MHz}$ )	C <sub>eb</sub>	WW.10	30	pF
Input Impedance (I <sub>C</sub> = -1.0 mAdc, V <sub>CE</sub> = -10 Vdc, f = 1.0 kHz)		1.5	15	kΩ
Voltage Feedback Ratio (I <sub>C</sub> = -1.0 mAdc, V <sub>CE</sub> = -10 Vdc, f = 1.0 kHz)		0.1	8.0	X 10 <sup>-4</sup>
Small–Signal Current Gain (I <sub>C</sub> = –1.0 mAdc, V <sub>CE</sub> = –10 Vdc, f = 1.0 kHz)		60	500	1.COM
Output Admittance ( $I_C = -1.0 \text{ mAdc}$ , $V_{CE} = -10 \text{ Vdc}$ , f = 1.0 kHz)	h <sub>oe</sub>	1.0	100	μmhos
SWITCHING CHARACTERISTICS	ONLI		L.WWW	N.V.C

	(VCC = -30 VUC, VEB = -2.0 VUC,	U L U			ne
Rise Time	$I_{C} = -150 \text{ mAdc}, I_{B1} = -15 \text{ mAdc})$	tr	_	20	.10031.
Storage Time	$(V_{CC} = -30 \text{ Vdc}, I_{C} = -150 \text{ mAdc},$	ts	_	225	06
Fall Time	$I_{B1} = I_{B2} = -15 \text{ mAdc}$	t <del>r</del>	<u> </u>	30	

3. Pulse Test: Pulse Width  $\leq$  300 µs, Duty Cycle  $\leq$  2.0%.

## SWITCHING TIME EQUIVALENT TEST CIRCUIT



Figure 1. Turn–On Time

Figure 2. Turn–Off Time

## TRANSIENT CHARACTERISTICS





h PARAMETERS V<sub>CE</sub> = -10 Vdc, f = 1.0 kHz, T<sub>A</sub> = 25°C

This group of graphs illustrates the relationship between  $h_{fe}$  and other "h" parameters for this series of transistors. To obtain these curves, a high–gain and a low–gain unit were







Figure 12. Voltage Feedback Ratio

selected from the MMBT4403LT1 lines, and the same units were used to develop the correspondingly–numbered curves on each graph.



Figure 11. Input Impedance







# STATIC CHARACTERISTICS



2.5

0.1 0.2

0.5 1.0 2.0

I<sub>C</sub>, COLLECTOR CURRENT (mA) Figure 16. "On" Voltages

50

100 200

500

5.0 10 20

0

0.1

0.2

0.5

1.0 2.0

I<sub>C</sub>, COLLECTOR CURRENT (mA) Figure 17. Temperature Coefficients

5.0 10 20

200

500

50 100

# **INFORMATION FOR USING THE SOT-23 SURFACE MOUNT PACKAGE**

### MINIMUM RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

Surface mount board layout is a critical portion of the total design. The footprint for the semiconductor packages must be the correct size to insure proper solder connection

interface between the board and the package. With the correct pad geometry, the packages will self align when subjected to a solder reflow process.







### SOT-23 POWER DISSIPATION

The power dissipation of the SOT–23 is a function of the pad size. This can vary from the minimum pad size for soldering to a pad size given for maximum power dissipation. Power dissipation for a surface mount device is determined by  $T_{J(max)}$ , the maximum rated junction temperature of the die,  $R_{\theta JA}$ , the thermal resistance from the device junction to ambient, and the operating temperature,  $T_A$ . Using the values provided on the data sheet for the SOT–23 package,  $P_D$  can be calculated as follows:

$$P_{D} = \frac{T_{J}(max) - T_{A}}{R_{\theta}JA}$$

The values for the equation are found in the maximum ratings table on the data sheet. Substituting these values into the equation for an ambient temperature  $T_A$  of 25°C, one can calculate the power dissipation of the device which in this case is 225 milliwatts.

$$P_{D} = \frac{150^{\circ}C - 25^{\circ}C}{556^{\circ}C/W} = 225 \text{ milliwatts}$$

The 556°C/W for the SOT–23 package assumes the use of the recommended footprint on a glass epoxy printed circuit board to achieve a power dissipation of 225 milliwatts. There are other alternatives to achieving higher power dissipation from the SOT–23 package. Another alternative would be to use a ceramic substrate or an aluminum core board such as Thermal Clad<sup>™</sup>. Using a board material such as Thermal Clad, an aluminum core board, the power dissipation can be doubled using the same footprint.

### SOLDERING PRECAUTIONS

The melting temperature of solder is higher than the rated temperature of the device. When the entire device is heated to a high temperature, failure to complete soldering within a short time could result in device failure. Therefore, the following items should always be observed in order to minimize the thermal stress to which the devices are subjected.

- Always preheat the device.
- The delta temperature between the preheat and soldering should be 100°C or less.\*
- When preheating and soldering, the temperature of the leads and the case must not exceed the maximum temperature ratings as shown on the data sheet. When using infrared heating with the reflow soldering method, the difference shall be a maximum of 10°C.
- The soldering temperature and time shall not exceed 260°C for more than 10 seconds.
- When shifting from preheating to soldering, the maximum temperature gradient shall be 5°C or less.
- After soldering has been completed, the device should be allowed to cool naturally for at least three minutes. Gradual cooling should be used as the use of forced cooling will increase the temperature gradient and result in latent failure due to mechanical stress.
- Mechanical stress or shock should not be applied during cooling.

\* Soldering a device without preheating can cause excessive thermal shock and stress which can result in damage to the device.

### MMBT4403LT1

# PACKAGE DIMENSIONS



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CASE 318-08 SOT-23 (TO-236AB) **ISSUE AE** 

NOTES:

DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

2 3.

T14.301, 1962. CONTROLLING DIMENSION: INCH. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.

DIM	INCHES		MILLIN	IETERS
	MIN	MAX	MIN	MAX
Α	0.1102	0.1197	2.80	3.04
В	0.0472	0.0551	1.20	1.40
С	0.0350	0.0440	0.89	1.11
D	0.0150	0.0200	0.37	0.50
G	0.0701	0.0807	1.78	2.04
Н	0.0005	0.0040	0.013	0.100
J	0.0034	0.0070	0.085	0.177
Κ	0.0180	0.0236	0.45	0.60
L	0.0350	0.0401	0.89	1.02
S	0.0830	0.0984	2.10	2.50
V	0.0177	0.0236	0.45	0.60



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